

Surface Mount Type

Series: H

SP-Cap

Japan



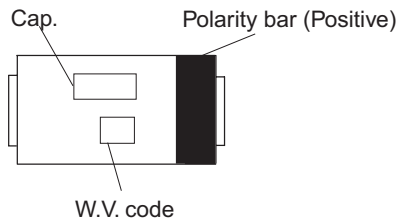
■ Features

- High Reliability (125°C)
- Low ESR & High Ripple Current

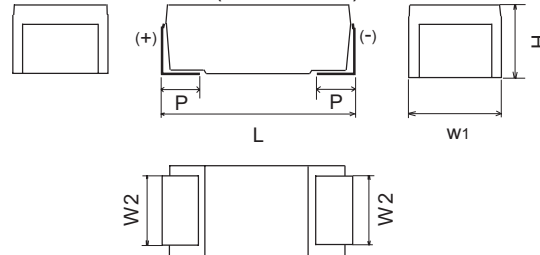
■ Specifications

Operating Temp. Range	-40 to +125°C	
Rated W.V. Range	2 to 8 V. DC	
Nominal Cap. Range	33 to 330 μF	
Capacitance Tolerance	±20 % (120Hz/+20°C)	
DC Leakage Current	$I \leq 0.1 CV$ after 2minutes	
Dissipation Factor	0.1 max. (120Hz/+20°C)	
Surge Voltage	Rated Working Voltage x 1.25 (+15 to +35°C)	
Endurance	After applying rated working voltage for 1000 hours or derated voltage (working voltage x 0.875 at 115°C or working voltage x 0.75 at 125°C) and then being stabilized at 20°C, the capacitor shall meet the following limits.	
	Capacitance change	±10% of initial measured value
	D.F.	≤ Initial specified value
Moisture Resistance	After storing for 500 hours at +60°C, 90%R.H.	
	Capacitance change	2, 2.5W.V.: +70%,-20%, 4W.V.: +60%,-20%, 6.3W.V.: +50%,-20%, 8W.V.: +40%,-20% of initial measured value.
	D.F.	≤ 200% of initial specified value
DC leakage current	Initial specified value	

■ Marking



■ Dimensions in mm(not to scale)



Size Code	L±0.2	W1±0.2	W2±0.1	H±0.1	P±0.3
HL	7.3	4.3	2.4	1.8	1.3
HD	7.3	4.3	2.4	2.8 ^{±0.2}	1.3
HE	7.3	4.3	2.4	4.2	1.3

■ Standard product

Series	Rated W.V. (V.DC)	Capacitance (± 20%) (μF)	Specification		Part Number	Min Pkg Q'ty (pcs)
			Ripple Current (A r.m.s./100kHz) +20 to 125°C	ESR (mΩ) max (100kHz/+20°C)		
*HL	2	100	1.8	18	EEFHL0D101R	3500
	2.5	82	1.8	18	EEFHL0E820R	3500
	4	56	1.8	18	EEFHL0G560R	3500
		68	1.8	18	EEFHL0G680R	3500
	6.3	47	1.8	18	EEFHL0J470R	3500
HD	2	180	2.5	15	EEFHD0D181R	2000
		220	2.5	15	EEFHD0D221R	2000
	2.5	150	2.5	15	EEFHD0E151R	2000
		180	2.5	15	EEFHD0E181R	2000
		120	2.5	15	EEFHD0G121R	2000
	6.3	100	2.5	15	EEFHD0J101R	2000
	8	68	2.5	15	EEFHD0K680R	2000
HE	2	270	3.0	12	EEFHE0D271R	2000
		330	3.0	12	EEFHE0D331R	2000
	2.5	220	3.0	12	EEFHE0E221R	2000
		270	3.0	12	EEFHE0E271R	2000
	4	180	3.0	12	EEFHE0G181R	2000
	6.3	150	3.0	12	EEFHE0J151R	2000
	8	100	3.0	12	EEFHE0K101R	2000

* Mass-production begins Q4/2002.